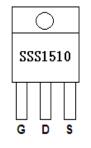
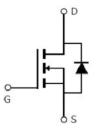


### **Main Product Characteristics**

V <sub>DSS</sub>	150V
R <sub>DS</sub> (on)	9.8mΩ (typ.)
I <sub>D</sub>	100A ①







TO-220

Marking and pin Assignment

Schematic diagram

### **Features and Benefits**

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



### **Description**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute max Rating**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	100 ①	
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	93 ①	А
I <sub>DM</sub>	Pulsed Drain Current ②	400	
Pp @TC = 25°C	Power Dissipation ③	300	W
PD @ IC = 25 C	Linear Derating Factor	2.0	W/°C
V <sub>DS</sub>	Drain-Source Voltage	150	V
$V_{GS}$	Gate-to-Source Voltage	± 20	V
Eas	Single Pulse Avalanche Energy @ L=0.3mH		mJ
I <sub>AS</sub>	Avalanche Current @ L=0.3mH	82.7	А
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +175	°C



### **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case ③	_	0.5	°C/W
В	Junction-to-ambient (t $\leq$ 10s) $\oplus$	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

## **Electrical Characterizes** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	150	_	_	V	$V_{GS} = 0V$ , $I_{D} = 1mA$
D			9.8	10.8	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> =100A
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	_	10	11	mΩ	V <sub>GS</sub> =8V,I <sub>D</sub> =50A
V	Cata threads and value as	2.0	_	4.0		$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.3	_	V	T <sub>J</sub> = 125°C
	Danie de Course la deservación		_	1	^	V <sub>DS</sub> =120V,V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source leakage current		_	50	μA	T <sub>J</sub> = 125°C
	Onto to Course forward backs on		_	100	nA	V <sub>GS</sub> =20V
I <sub>GSS</sub>	Gate-to-Source forward leakage		_	-100		V <sub>GS</sub> = -20V
t <sub>d(on)</sub>	Turn-on delay time		33	_		V <sub>GS</sub> =10V, V <sub>DD</sub> =75V,
t <sub>r</sub>	Rise time		105	_	nS	$R_L=0.75\Omega$ ,
t <sub>d(off)</sub>	Turn-Off delay time		73	_		R <sub>GEN</sub> =1.6Ω
t <sub>f</sub>	Fall time		19	_		I <sub>D</sub> =100A
Ciss	Input capacitance	_	5634	_		$V_{GS} = 0V$
Coss	Output capacitance	_	657	_	pF	V <sub>DS</sub> = 50V
C <sub>rss</sub>	Reverse transfer capacitance	_	12.6	_		f = 1MHz

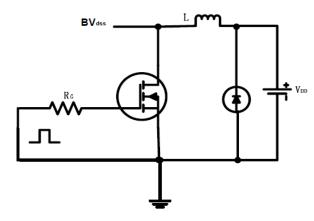
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			100 ①	^	MOSFET symbol
Is	(Body Diode)	_	_	100 ①	A	showing the
I <sub>SM</sub>	Pulsed Source Current			400	А	integral reverse
	(Body Diode)	_	_			p-n junction diode.
$V_{\text{SD}}$	Diode Forward Voltage	_	0.94	1.3	V	I <sub>S</sub> =100A, V <sub>GS</sub> =0V,
						$T_J = 25$ °C

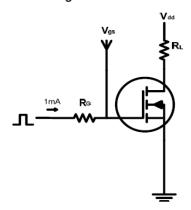


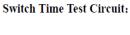
### **Test circuits and Waveforms**

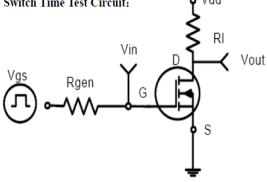
#### EAS test circuits:



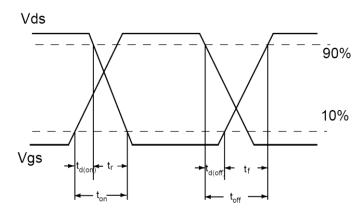
#### Gate charge test circuit:







#### **Switch Waveforms:**

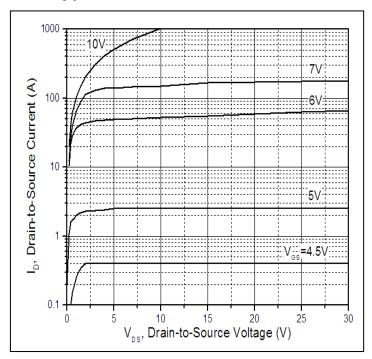


### **Notes:**

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4 The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



## Typical electrical and thermal characteristics



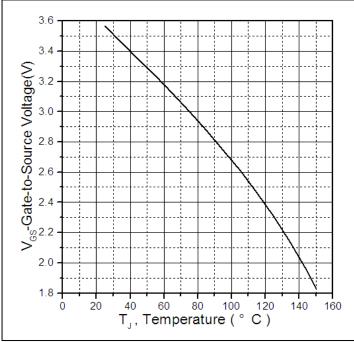
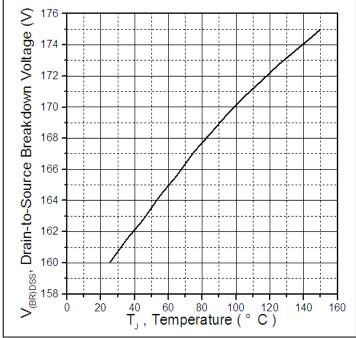


Figure 1: Typical Output Characteristics







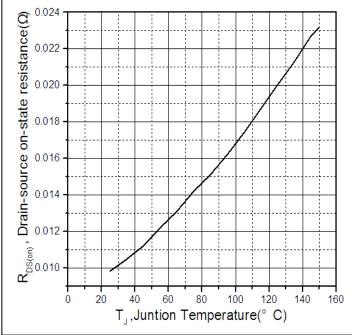
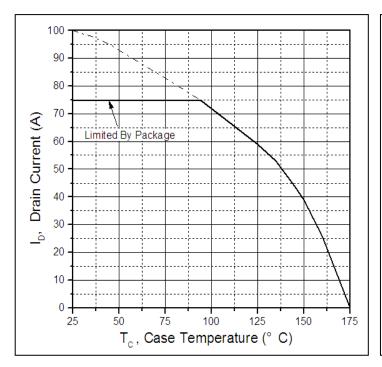


Figure 4: Normalized On-Resistance Vs. Case **Temperature** 



## Typical electrical and thermal characteristics



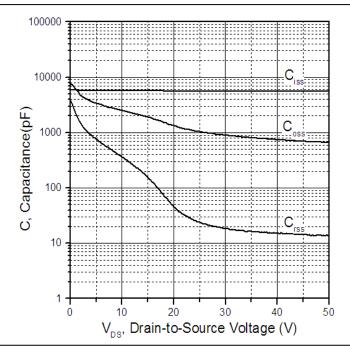


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

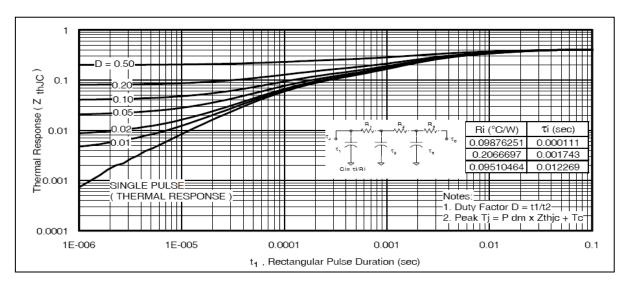
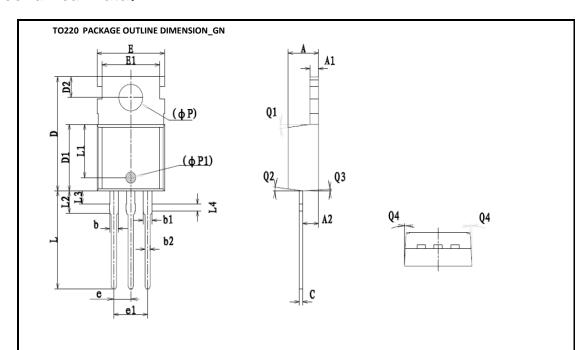


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



# **Mechanical Data:**



Symbol	Dime	nsion In Millin	neters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
Α	4.400	4.550	4.700	0.173	0.179	0.185	
A1	1.270	1.300	1.330	0.050	0.051	0.052	
A2	2.240	2.340	2.440	0.088	0.092	0.096	
b	-	1.270	_	-	0.050	-	
b1	1.270	1.370	1.470	0.050	0.054	0.058	
b2	0.750	0.800	0.850	0.030	0.031	0.033	
С	0.480	0.500	0.520	0.019	0.020	0.021	
D	15.100	15.400	15.700	0.594	0.606	0.618	
D1	8.800	8.900	9.000	0.346	0.350	0.354	
D2	2.730	2.800	2.870	0.107	0.110	0.113	
E	9.900	10.000	10.100	0.390	0.394	0.398	
E1	-	8.700	-	-	0.343	-	
ΦР	3.570	3.600	3.630	0.141	0.142	0.143	
ФР1	1.400	1.500	1.600	0.055	0.059	0.063	
е		2.54BSC		0.1BSC			
e1		5.08BSC		0.2BSC			
L	13.150	13.360	13.570	0.518	0.526	0.534	
L1		7.35REF		0.29REF			
L2	2.900	3.000	3.100	0.114	0.118	0.122	
L3	1.650	1.750	1.850	0.065	0.069	0.073	
L4	0.900	1.000	1.100	0.035	0.039	0.043	
Q1	5 <sup>0</sup>	7 <sup>0</sup>	90	5 <sup>0</sup>	<b>7</b> <sup>0</sup>	9 <sup>0</sup>	
Q2	5 <sup>0</sup>	7 <sup>0</sup>	9 <sup>0</sup>	5 <sup>0</sup>	<b>7</b> <sup>0</sup>	9 <sup>0</sup>	
Q3	5 <sup>0</sup>	7 <sup>0</sup>	90	5 <sup>0</sup>	7 <sup>0</sup>	9 <sup>0</sup>	
Q4	1 <sup>0</sup>	3 <sup>0</sup>	5 <sup>0</sup>	1 <sup>0</sup>	3 <sup>0</sup>	5 <sup>0</sup>	



## **Ordering and Marking Information**

Device Marking: SSS1510

Package (Available)
TO-220
Operating Temperature Range
C: -55 to 175 °C

## **Devices per Unit**

Package	Units/	Tubes/Inner	Units/Inner		Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
				Pov	
				Box	

## **Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V <sub>DSS</sub> /V <sub>CES</sub> /VR	1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =125℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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